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/ Ruth Montalvo

Date: 04/29/05

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: GK-ZEI-3269/500343.20289

U.S. Application No.:

International Application No.: PCT/EP2004/006302

International Filing Date: JUNE 11, 2004

11 JUNE 2004

Priority Date Claimed: JUNE 12, 2003

12 JUNE 2003

Title of Invention:

METHOD FOR DETERMINING THE IMAGE QUALITY OF AN OPTICAL IMAGING SYSTEM

Applicant(s) for (DO/EO/US):

Thomas ENGEL and Herbert GROSS

Mail Stop PCT
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INFORMATION DISCLOSURE STATEMENT

S I R:

Applicant herewith submits together with the simultaneously filed National Phase application of PCT/EP2004/006302, a copy of the International Search Report (PCT/ISA/210) dated October 20, 2004 and German Examination Report (103 27 019.1) dated March 4, 2004, citing some of the following references:

	Document Number	Date	Name and/or Country	English Translation
AA	5,066,119	11/19/1991	Bertand	
AB	2002/0057495	05/16/2002	Kuramoto	
AL	38 42 144	06/21/1990	Germany	Abstract only
AM	95/34800	12/21/1995	WIPO	
AN	10-170399	06/26/1998	Japan	Abstract only
AO	99/66308	12/23/1999	WIPO	
AP	1 079 223	02/28/2001	European	
AQ	1 246 014	10/02/2002	European	
AR	101 54 125	05/22/2003	Germany	Abstract only

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AX Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995

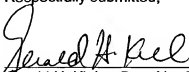
AY Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992

Accompanying this Information Disclosure Statement and form PTO-1449 are copies of the 7 foreign documents including 3 English Abstracts, first pages of the 2 U.S. documents excepted articles AX and AY. Articles AX-AY are mentioned on page 3 of the substitute specification.

The USPTO waived the requirement under 37 C.F.R. §1.98(a)(2)(i) for submitting copies of US patents and US patent application publications in all U.S. applications filed after June 30, 2003.

This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,



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04/29/05
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Enclosures:

Search Reports (PCT/ISA/210);
German Examination Report
PTO-1449;
2 U.S. first pages
7 documents
3 English Abstracts

LIST OF PRIOR ART CITED BY APPLICANT
(Filed on April 29, 2005)

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Docket No. GK-ZEI-3269/500343.20289

Applicant(s): Thomas ENGEL and Herbert GROSS

Application No. (Int'l Appln No. PCT/EP2004/006302 11JUNE04) Group:

Filed: Concurrently herewith - April 29, 2005

Examiner:

U.S. PATENT DOCUMENTS

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AA	5,066,119	11/19/1991	Bertand			
	AB	2002/0057495	05/16/2002	Kuramoto			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	CLASS	Sub-Class	Translation YES	NO
	AL	38 42 144	06/21/1990	Germany			Abstract only	
	AM	95/34800	12/21/1995	WIPO				
	AN	10-170399	06/26/1998	Japan			Abstract only	
	AO	99/66308	12/23/1999	WIPO				
	AP	1 079 223	02/28/2001	European				
	AQ	1 246 014	10/02/2002	European				
	AR	101 54 125	05/22/2003	Germany			Abstract only	
	AS							
	AT							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AX	Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995
	AY	Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992
	AZ	

Examiner: /Manav Seth/

Date: 09/14/2008

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /M.S./